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<th>A New Measurement System for the Perpendicular Complex Permittivity to DUT Sheet by Stripline Simulation</th>
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<td>Suzuki, Hirosuke; Hotchi, Tomio; Nojima, Toshio</td>
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**Abstract**

A new measurement system for the perpendicular complex permittivity to DUT sheet by stripline simulation is presented. The system consists of a stripline probe and a network analyzer. The stripline probe is designed to measure the complex permittivity of the DUT sheet perpendicular to the probe. The network analyzer is used to measure the transmission and reflection coefficients of the stripline probe. The measured results are compared with the theoretical values to verify the accuracy of the measurement system.

**Keywords**

Perpendicular complex permittivity, DUT sheet, stripline simulation, network analyzer.
A new Measurement system for the perpendicular complex permittivity to DUT-sheet by stripline simulation

Hirosuke SUZUKI, Member, IEEE, Tomio HOTCHI and Toshio NOJIMA, Member, IEEE

Abstract—The relative dielectric constant, \( \varepsilon_r \), is calculated by quasi-static and frequency-dependent hybrid-mode analysis of two layers of dielectric materials (a sample material and a resonator base material) after measuring the rate of change of the resonating frequency of a sheet material under test sandwiched between sheet metal and a calibrated stripline resonator. This method corrects the fringing effect of the resonator by using two resonators that have slightly different resonating frequencies. In the present study, \( \tan \delta \) is calculated by balancing the conductor loss.

The features of this method are as follows:
1) Measurement of \( \varepsilon_r \) and \( \tan \delta \) is accurate.
2) Measurement can occur at several frequencies simultaneously.
3) Measurement can be made of \( \varepsilon_r \) and \( \tan \delta \) in the E direction perpendicular to the sheet material, e.g., a printed circuit board.
4) A metal pattern is not required. Only the sheet material under test is necessary.
5) Measurement provides accurate data since there is no radiation loss.

This method is useful for measurement in the range 0.5–14 GHz, calculated at multiple frequencies. Fully automatic calculation can be achieved by computer analysis through connection to a network analyzer.

Keywords—Complex permittivity, Stripline resonator, Simulation, Non-pattern fabrication, Multi-frequency measurement.

I. INTRODUCTION

Many types of devices with a printed circuit antenna, resonator, and circulator, such as mobile phones and automobile collision avoidance radar systems, have been developed. The printed circuit board requires accurate values of the relative dielectric constant \( \varepsilon_r \) and low \( \tan \delta \).

The following are some examples of recent requirements for permittivity measurement:
1) Accurate measurement of \( \varepsilon_r \) and \( \tan \delta \).
2) Measurement of \( \varepsilon_r \) and \( \tan \delta \) in the E-H field direction of materials used in testing, e.g., printed circuit boards.
3) Non-metal pattern fabrication for measurement of \( \varepsilon_r \) and \( \tan \delta \).
4) Measurement at several frequencies simultaneously.
5) Easy measurement or shortened measuring time (within 5 minutes).
6) Measurement that provides accurate data.

While the stripline resonator method [1][2] satisfies item 2), metal fabrication of a stripline is very difficult and requires many hours for testing \( \varepsilon_r \) and \( \tan \delta \). The alternative microstrip resonator method employs the novel concept of using simulation software for calculating the unknown \( \varepsilon_r \), of a sample material from three different \( \varepsilon_r \) materials: air, the sample sheet material, and the microstrip resonator [3]. However, the value of measured \( \tan \delta \) is not accurate because the microstrip suffers radiation loss. The problem of measured \( \tan \delta \) has been improved, however, by a method we outlined in a previous publication [4].

Although the cavity perturbation method is highly accurate for measuring complex permittivity [5], the E direction of \( \varepsilon_r \) and \( \tan \delta \) is parallel to the sheet material. In the present paper, to overcome the problems of measurement at different frequencies, the measurement ratio of \( \varepsilon_r \) between the perpendicular and the parallel E directions to the DUT sheet is calculated. Here, \( \varepsilon_r \) is...
fully calculated by quasi-static and frequency-dependent hybrid-mode analysis of two layers of dielectric materials (a sample material and a resonator base material) after measuring the rate of change of the resonating frequency of a sheet material under test sandwiched between sheet metal and a calibrated stripline resonator. The method corrects the fringing effect of the resonator by using two resonators that have slightly different resonating frequencies. In addition, \( \tan \delta \) is accurately calculated by balancing the conductor loss. This method is useful for the accurate measurement of \( \varepsilon_r \) and \( \tan \delta \) in the E direction perpendicular to the sheet material (e.g., printed circuit board) and in the range 0.5–14 GHz, calculated simultaneously at multiple frequencies. Fully automatic calculation can be achieved by computer analysis through connection to a network analyzer.

II. OUTLINE OF THE NEW APPROACH

Figure 1 shows the newly developed automatic measurement system using the stripline resonator technique.

To ensure close contact of the sample sheet with the microstripline resonator, a weighted metal plate is placed on the sample.

FIG.1 HERE

Symbols are as follows:
- \( f_{o1} \) [GHz]: resonance dominant frequency of resonator \( R_a \) for fringing effect correction contacting the same material as \( R_s \)
- \( L_o \) [mm]: \( \frac{\lambda_{o2}}{2}, \frac{\lambda_{o1}}{2} = \frac{c}{f_{o1}} \)
  - \( c \): speed of light
- \( f_{s1} \) [GHz]: resonance dominant frequency of resonator \( R_s \) contacting the same material as \( R_s \)
- \( Q_{s1} \): dominant Q factor of resonator \( R_s \) contacting the same material as \( R_s \)
- \( L_s \) [mm]: \( L_s \times 1.1 \)
- \( h \) [mm]: thickness of material of resonators \( R_a \) and \( R_s \)
- \( d \) [mm]: thickness of material under test
- \( w \) [mm]: metal pattern of \( R_a \) and \( R_s \)
- \( f_{n1} \) [GHz]: resonance dominant frequency of resonator \( R_s \) contacting the material under test
- \( Q_{n1} \): Q factor of resonator \( R_s \) contacting the material under test

The microstripline resonators \( R_a \) and \( R_s \) are composed of:
- a low- \( \varepsilon_r \) and a low- \( \tan \delta \) material such as polytetrafluoroethylene (PTFE), a thin copper resonator, and are 9 \( \mu \)m in thickness. The 2 GHz resonators are shown in Fig.2.

FIG.2 HERE

The dielectric materials of resonator \( R_a \) for fringing effect correction and resonator \( R_s \) for measurement must be the same.
1) \( f_{o1} \) is measured by a network analyzer or similar device.
2) \( f_{s1} \) is measured by the same device.
3) Electromagnetic waves expand slightly from the edge of the resonator; a phenomenon known as the fringing effect.

\( \Delta L \) : fringing length

The difference between \( f_{o1} \) and \( f_{s1} \) is only 10%. Thus, the dominant fringing lengths \( \Delta L_o \) of \( L_o \) and \( L_s \) are identical. So,

\[
f_{o1}(L_o + \Delta L_o) = f_{s1}(L_s + \Delta L_s)
\]

\[
\therefore \Delta L_s = \frac{f_{o1}L_o - f_{s1}L_s}{f_{o1} - f_{s1}}
\]  \hspace{1cm} (1)

\( L_o \) x 1.05, \( L_o \) x 1.1, and \( L_o \) x 1.15 to \( L_s \) were tested to decide \( \Delta L_s \). Based on the results, \( L_o \) x 1.1 to \( L_s \) was adopted.

4) The calculation of \( \varepsilon_{r1} \) of resonator \( R_s \) with the same dielectric material as resonator \( R_a \) is expressed by Eq. (2).

\[
\varepsilon_{r1} = \frac{c}{2(L_s + \Delta L_s) f_{s1}} \cdot \frac{1}{\sqrt{\varepsilon_{r1}}}
\]

\[
\therefore \varepsilon_{s1} = \left( \frac{c}{2(L_s + \Delta L_s) f_{s1}} \right)^2 \hspace{1cm} (2)
\]

Note: the dominant mode of resonance is half wave.

FIG.3 HERE

5) Resonator \( R_s \) with the material under test is written as below. Figure 3 shows the relationship between \( \varepsilon_{r1} \), \( \tan \delta_1 \) and \( \varepsilon_{r2} \), \( \tan \delta_2 \) and effective \( \varepsilon_{r2} \). \( \varepsilon_{r2} \) and effective \( \tan \delta_2 \) \( (\tan \delta_{2\text{eff}}) \).

Here, \( f_{n1} \) and \( Q_{n1} \) are measured by resonator \( R_s \) with the material under test.

( \( \varepsilon_{r2\text{eff}} \) ) is calculated as follows:
2(L_s + ΔL_1) = \frac{c}{f_{m1}} \cdot \frac{1}{\sqrt{ε_{r,eff}^2}}

\therefore ε_{r,eff} = \left( \frac{c}{2(L_s + ΔL_1)f_{m1}} \right)^2 \quad \cdots(3)

III. CALCULATION OF ε_{r1} IN THE CASE OF SEVERAL FREQUENCIES

FIG.4 HERE

In this case, ΔL_2 is calculated as follows:

\[ f_{a2} \left( \frac{L_s}{2} + ΔL_2 \right) = f_{s2} \left( \frac{L_s}{2} + ΔL_2 \right) \]

\therefore ΔL_2 = \frac{f_{s2}L_s - f_{a2}L_f}{2(f_{a2} - f_{s2})} \quad \cdots(4)

By the same process,

\therefore ΔL_3 = \frac{f_{s3}L_s - f_{a3}L_f}{3(f_{a3} - f_{s3})} \quad \cdots(5)

Symbols are as follows:

f_{a2}, f_{a3}: second and third resonance frequencies of f_{a1}
f_{s2}, f_{s3}: second and third resonance frequencies of f_{s1}
ΔL_2, ΔL_3: fringing length of second and third resonance frequencies

Note that the method is not limited to 3 frequencies.

IV. CALCULATION OF ε_{r2} BY COMPUTER

Next, ε_{r2} is calculated numerically [5].
Coupled strips with an overlay structure (Fig.8 of Reference [5]) are used to calculate ε_{r2}.
The layer structure is illustrated in Fig.3 and photographs of the layer structure are shown in Fig.5.

FIG.5 HERE

ε_{r2} is obtained by the following steps:
1) Computer program,
\[ ε_{r2,eff} = \text{function (h/f_2, w, } ε_{r1}, d, ε_{r2}, \text{ metal)} \quad \cdots(6) \]

Note that the upper area of the sample is composed of metal.
2) Next, ε_{r} is changed to 1,000 from 0 in 0.0001 steps.

Figure 6 shows the process of determining ε_{r2} (the sample’s ε_{r}).
Thus, the function (h/f_2, w, ε_{r1}, d, ε_{r2}, metal) approaches ε_{r2} in a step-by-step manner, and when the left-hand side of Eq. (6) becomes equal to the right-hand side, we have

ε_{r} = ε_{r2}

In this equation, the function increases or decreases monotonically with ε_{r}.

FIG.6 HERE

V. DETERMINATION OF tan δ_{cond}

\[ \tan δ_{eff} = \tan δ_{rad} + \tan δ_{cond} + \tan δ_{1} \quad \cdots(7) \]

Since

\[ \tan δ_{eff} = \frac{1}{Q_{r1}} \quad \cdots(8) \]

\[ \tan δ_{rad} = 0 \]

because the stripline does not radiate EM waves.
Symbols are as follows:

tan δ_{rad}: tan δ caused by radiation loss of resonator R_s
tan δ_{cond}: tan δ caused by conductor loss of resonator R_s
tan δ_{1}: dielectric loss of resonator R_s

\[ \therefore \tan δ_{rad} + \tan δ_{cond} = \frac{1}{Q_{r1}} - \tan δ_{1} \]

and

\[ \tan δ_{rad} = 0 \]

\[ \therefore \tan δ_{cond} = \frac{1}{Q_{r1}} - \tan δ_{1} \quad \cdots(9) \]

VI. tan δ_{2} CALCULATED BY EFFECTIVE

\[ \tan δ_{2} = (\tan δ_{2,eff}) \]

If the ε_{r} of the material is small, (tan δ_{rad} + tan δ_{cond}) hardly changes before and after measurement when the material under test is placed on the stripline resonator.

\[ \therefore \tan δ_{2,eff} = \tan δ_{rad} + \tan δ_{cond} + (\tan δ_{1} / \tan δ_{2}) \]

[\tan δ_{rad} = 0]
\[ \therefore \tan \delta_{\text{eff}} = \tan \delta_{\text{cond}} + (\tan \delta_1 / \tan \delta_2) \quad \text{(10)} \]

\[ \tan \delta_{\text{eff}} = \frac{1}{Q_{m1}} \]

and by inserting Eq. (9) into Eq. (10).

\[ \frac{1}{Q_{m1}} = \frac{1}{Q_{s1}} - \tan \delta_1 + (\tan \delta_1 / \tan \delta_2) \quad \text{(11)} \]

\[ \therefore (\tan \delta_1 / \tan \delta_2) = \frac{1}{Q_{m1}} - \frac{1}{Q_{s1}} + \tan \delta_1 \quad \text{(12)} \]

If the lines of electric force are perpendicular to the material plane, then generally (\( \tan \delta_1 / \tan \delta_2 \)) is obtained as follows:

\[ (\tan \delta_1 / \tan \delta_2) = \frac{\epsilon_{r2} h \cdot \tan \delta_1 + \epsilon_{r1} d \cdot \tan \delta_2}{\epsilon_{r2} \cdot h + \epsilon_{r1} \cdot d} \quad \text{(13)} \]

\[ \therefore \tan \delta_2 = \frac{(\tan \delta_1 / \tan \delta_2) (\epsilon_{r2} \cdot h + \epsilon_{r1} \cdot d) - \epsilon_{r2} \cdot h \cdot \tan \delta_1}{\epsilon_{r1} \cdot d} \quad \text{(14)} \]

Equation (14) can be substituted by Eq. (12).

\[ \therefore \tan \delta_2 = \frac{\epsilon_{r2} \cdot h + \epsilon_{r1} \cdot d}{\epsilon_{r1} \cdot d} \left( \frac{1}{Q_{m1}} - \frac{1}{Q_{s1}} \right) + \tan \delta_1 + \alpha \quad \text{(15)} \]

\( \alpha \) : correction number

When PTFE is used for calibrating \( \tan \delta \), we measure \( \tan \delta_2 \) of the PTFE by employing another measurement technique, namely, either the perturbation resonator method [5] or the open-type resonator (Fabry-Perot resonator) method [7]. These methods are useful to measure \( \epsilon_r \) and \( \tan \delta \) for an isotropic material in general because the E direction of \( \epsilon_r \) and \( \tan \delta \) is parallel to the sheet material.

Using the perturbation resonator method, we determined \( \tan \delta \) of PTFE to be 0.0004 in the range 1–15GHz. Further, we control \( \alpha \) to achieve \( \tan \delta_2 \) which is equal to \( \tan \delta \) as determined by the other measuring technique.

In the case of the second and third resonance frequencies, \( Q_{m1}, Q_{s1} \) is read at \( Q_{m2}, Q_{s2} \) and \( Q_{m3}, Q_{s3} \).

VII. RESULTS

Screenshots showing the three resonance points are shown in Fig.7, and we can see the dielectric constant relationship that exists between these frequencies.

FIG.7 HERE

Table 1 HERE

The results for an isotropic dielectric sheet using the stripline resonator method are shown in Table 1. The results for the perturbation resonator method are shown in Table 2.

Table 2 HERE

The results for the anisotropic dielectric sheets using the stripline resonator method are shown in Table 2.

The quality factor \( Q \) of glass fiber net and immersed PTFE resin. The \( \epsilon_r \) of glass is higher than that of PTFE, and thus the \( \epsilon_r \) in the E direction parallel to the sheet will be higher than
in the E direction perpendicular to it. In the case of using the perturbation resonator, the $\varepsilon_r$ in the E direction is parallel to the sheet. The $\varepsilon_r$ of fiber-reinforced PTFE determined by the perturbation resonator method is 2.42, which is higher than that of the new stripline resonator method (2.17). Fiber-reinforced EPOXY has a similar property. The ratios of $\varepsilon_r$ between the E directions perpendicular and parallel to the DUT sheet are shown at bottom of Table 2. The obtained values of 0.895 in the case of a fiber-reinforced PTFE and 0.93 in the case of a fiber-reinforced EPOXY at 2.7GHz are extremely important information to the electronic engineering field. An illustration, when designing a printed circuit antenna made with fiber-reinforced PTFE for an automobile collision avoidance radar system at 76.5GHz, $\varepsilon_r \perp$ at 76.5GHz is needed. So, $\varepsilon_r //\times 0.895$ which overcomes the difficulty at present of not being able to measure $\varepsilon_r \perp$ directly at millimeter wave frequencies.

**VIII. Conclusions**

The dielectric constant $\varepsilon_r$ and loss $\tan \delta$ of a sheet material can be measured with high accuracy and very easily by employing the new stripline resonator method. The features of the proposed method for measuring $\varepsilon_r$ and $\tan \delta$ are as follows:

1) Measurement of $\varepsilon_r$ and $\tan \delta$ is accurate.
2) Measurement can occur at several frequencies simultaneously.
3) Measurement can be made of $\varepsilon_r$ and $\tan \delta$ in the E direction perpendicular to the sheet material. In addition, $\varepsilon_r //\times 0.895$ which overcomes the difficulty at present of not being able to measure $\varepsilon_r \perp$ directly at millimeter wave frequencies.
4) A metal pattern is not required. Only the sheet material under test is necessary.
5) Measurement provides accurate data since there is no radiation loss.

Future plans to improve this method aim at the development of a new, thinner film material by changing the $\tan \delta$ calculation method.

**REFERENCES**


[2] IPC-TM-650 2.5.5.5.1 “Stripline Test for Complex Relative Permittivity of circuit Board Materials to 14GHz” Institute of Printed Circuits, USA.


Fig. 1 Automatic measuring system using the stripline resonator method.

Fig. 2 2 GHz resonators for fringing effect correction and for material measurement.

Fig. 3 Relationship between $\varepsilon_{r1}$, $\tan \delta_1$, $\varepsilon_{r2}$, $\tan \delta_2$, $\varepsilon_{r2 \text{eff}}$ and $\tan \delta_{2\text{eff}}$

Fig. 4 Resonance at several frequencies

Fig. 5 Photograph of the 2-layer structure

Fig. 6 Process of determination of $\varepsilon_{r2 \text{eff}}$. 
Fig. 7 Screenshots of three resonance points obtained using the stripline resonator method

Fig. 8 Apparatus of the perturbation resonator method
### Table 1

$\varepsilon_r$ and $\tan\delta$ of the isotropic materials PTFE, TPX and PE sheets obtained by the stripline resonator method.

<table>
<thead>
<tr>
<th>Resonator fiber [reinforced PTFE]</th>
<th>$L_f$ [mm]</th>
<th>$L_e$ [mm]</th>
<th>$f_1$ [GHz]</th>
<th>$f_2$ [GHz]</th>
<th>$f_3$ [GHz]</th>
<th>$\Delta\varepsilon_1$</th>
<th>$\Delta\varepsilon_2$</th>
<th>$\Delta\varepsilon_3$</th>
<th>$\Delta\varepsilon_{\tan}$</th>
</tr>
</thead>
<tbody>
<tr>
<td>PTFE</td>
<td>21.9 (W=4.2mm, h=0.8mm)</td>
<td>2.10168</td>
<td>4.39921</td>
<td>4.3898</td>
<td>4.36842</td>
<td>0.00150</td>
<td>0.00150</td>
<td>0.00150</td>
<td>0.00150</td>
</tr>
<tr>
<td>PE</td>
<td>22.5 (W=4.2mm, h=0.8mm)</td>
<td>2.10150</td>
<td>4.38973</td>
<td>4.36842</td>
<td>4.36813</td>
<td>0.00150</td>
<td>0.00150</td>
<td>0.00150</td>
<td>0.00150</td>
</tr>
</tbody>
</table>

### Samples

- Material: PTFE, TPX, PE
- $d$ [mm]: 1.074, 1.48

<table>
<thead>
<tr>
<th>Results [GHz]</th>
<th>$f_1$</th>
<th>$f_2$</th>
<th>$f_3$</th>
<th>$\varepsilon_r$</th>
<th>$\tan\delta$</th>
</tr>
</thead>
<tbody>
<tr>
<td>4.38973</td>
<td>4.39921</td>
<td>4.36842</td>
<td>4.36842</td>
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<td>0.00150</td>
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<td>4.36842</td>
<td>4.39921</td>
<td>4.38973</td>
<td>4.38973</td>
<td>0.00150</td>
<td>0.00150</td>
</tr>
</tbody>
</table>

**Note:** PTFE: Polytetrafluoroethylene

TPX: Polymethylpentene

PE: Polyethylene

$\varepsilon_r \perp$: $\varepsilon_r$ of E direction perpendicular to the sheet

$\varepsilon_r \parallel$: $\varepsilon_r$ of E direction parallel to the sheet

Calibration of $\tan\delta$: The $\tan\delta_2$ of PTFE is adjusted to 0.0004* by controlling $\alpha$.

### Table 2

$\varepsilon_r$ and $\tan\delta$ of the anisotropic materials fiber-reinforced PTFE and fiber-reinforced EPOXY sheets obtained by the stripline resonator method.

<table>
<thead>
<tr>
<th>Resonator fiber [reinforced PTFE]</th>
<th>$L_f$ [mm]</th>
<th>$L_e$ [mm]</th>
<th>$f_1$ [GHz]</th>
<th>$f_2$ [GHz]</th>
<th>$f_3$ [GHz]</th>
<th>$\Delta\varepsilon_1$</th>
<th>$\Delta\varepsilon_2$</th>
<th>$\Delta\varepsilon_3$</th>
<th>$\Delta\varepsilon_{\tan}$</th>
</tr>
</thead>
<tbody>
<tr>
<td>Fiber-reinforced PTFE</td>
<td>34.55 (W=4.0mm, h=0.8mm)</td>
<td>36.15 (W=4.0mm, h=0.8mm)</td>
<td>2.15140</td>
<td>2.14902</td>
<td>4.39921</td>
<td>0.00150</td>
<td>0.00150</td>
<td>0.00150</td>
<td>0.00150</td>
</tr>
<tr>
<td>Fiber-reinforced EPOXY</td>
<td>2.1661</td>
<td>2.15140</td>
<td>2.15140</td>
<td>2.14904</td>
<td>2.15949</td>
<td>0.00150</td>
<td>0.00150</td>
<td>0.00150</td>
<td>0.00150</td>
</tr>
</tbody>
</table>

### Samples

- Material: Fiber-reinforced PTFE, Fiber-reinforced EPOXY
- $d$ [mm]: 0.80, 1.50

<table>
<thead>
<tr>
<th>Results [GHz]</th>
<th>$f_1$</th>
<th>$f_2$</th>
<th>$f_3$</th>
<th>$\varepsilon_r$</th>
<th>$\tan\delta$</th>
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<td>4.38973</td>
<td>4.38973</td>
<td>0.00150</td>
<td>0.00150</td>
</tr>
</tbody>
</table>

**Note:** Glass PTFE, Glass EPOXY: PTFE and EPOXY reinforced by glass fiber net.

$\varepsilon_r \perp$: $\varepsilon_r$ of E direction perpendicular to the sheet

$\varepsilon_r \parallel$: $\varepsilon_r$ of E direction parallel to the sheet

$\Delta\varepsilon_{\tan}$: $\tan\delta$ of the fiber net.